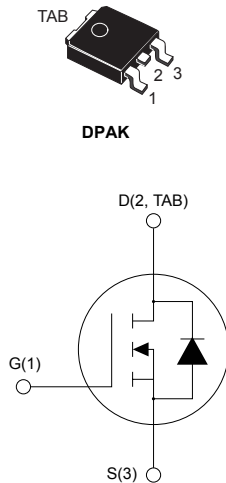


Automotive-grade N-channel 60 V, 14 mΩ typ., 35 A STripFET II Power MOSFET in a DPAK package



AM01475v1_noZen



Features

Order code	V_{DS}	$R_{DS(on)}$ max.	I_D
STD35NF06LT4	60 V	17 mΩ	35 A

- AEC-Q101 qualified 
- Exceptional dv/dt capability
- Low gate charge
- Logic level $V_{GS(th)}$
- 100% avalanche tested

Applications

- Switching applications

Description

This Power MOSFET has been developed using STMicroelectronics' unique STripFET process, which is specifically designed to minimize input capacitance and gate charge. This renders the device suitable for use as primary switch in advanced high-efficiency isolated DC-DC converters for telecom and computer applications, and applications with low gate charge driving requirements.

Product status link

[STD35NF06LT4](#)

Product summary

Order code	STD35NF06LT4
Marking	D35NF06L
Package	DPAK
Packing	Tape and reel

1 Electrical ratings

Table 1. Absolute maximum ratings

Symbol	Parameter	Value	Unit
V_{DS}	Drain-source voltage	60	V
V_{GS}	Gate-source voltage	± 16	V
I_D	Drain current (continuous) at $T_C = 25\text{ }^{\circ}\text{C}$	35	A
	Drain current (continuous) at $T_C = 100\text{ }^{\circ}\text{C}$	24.5	
$I_{DM}^{(1)}$	Drain current (pulsed)	140	A
P_{TOT}	Total power dissipation at $T_C = 25\text{ }^{\circ}\text{C}$	80	W
$dv/dt^{(2)}$	Peak diode recovery voltage slope	5	V/ns
T_{stg}	Storage temperature range	-55 to 175	$^{\circ}\text{C}$
T_J	Operating junction temperature range		$^{\circ}\text{C}$

1. Pulse width limited by safe operating area.
2. $I_{SD} \leq 35\text{ A}$, $di/dt \leq 100\text{ A}/\mu\text{s}$, $V_{DS}(\text{peak}) < V_{(BR)DSS}$.

Table 2. Thermal data

Symbol	Parameter	Value	Unit
R_{thJC}	Thermal resistance, junction-to-case	1.88	$^{\circ}\text{C}/\text{W}$
$R_{thJA}^{(1)}$	Thermal resistance, junction-to-ambient	50	$^{\circ}\text{C}/\text{W}$

1. When mounted on a standard 1 inch² area of FR-4 PCB with 2-oz copper.

Table 3. Avalanche characteristics

Symbol	Parameter	Value	Unit
I_{AR}	Avalanche current, repetitive or non-repetitive (pulse width limited by T_J max.)	30	A
E_{AS}	Single pulse avalanche energy (starting $T_J = 25\text{ }^{\circ}\text{C}$, $I_D = I_{AR}$, $V_{DD} = 30\text{ V}$)	280	mJ

2 Electrical characteristics

$T_C = 25\text{ }^{\circ}\text{C}$ unless otherwise specified.

Table 4. On/off states

Symbol	Parameter	Test conditions	Min.	Typ.	Max.	Unit
$V_{(BR)DSS}$	Drain-source breakdown voltage	$I_D = 250\text{ }\mu\text{A}$, $V_{GS} = 0\text{ V}$	60	-	-	V
I_{DSS}	Zero gate voltage drain current	$V_{GS} = 0\text{ V}$, $V_{DS} = 60\text{ V}$	-	-	1	μA
		$V_{GS} = 0\text{ V}$, $V_{DS} = 60\text{ V}$, $T_C = 125\text{ }^{\circ}\text{C}^{(1)}$	-	-	10	
I_{GSS}	Gate-body leakage current	$V_{DS} = 0\text{ V}$, $V_{GS} = \pm 18\text{ V}$	-	-	± 100	nA
$V_{GS(th)}$	Gate threshold voltage	$V_{DS} = V_{GS}$, $I_D = 250\text{ }\mu\text{A}$	1	-	2.5	V
$R_{DS(on)}$	Static drain-source on-resistance	$V_{GS} = 10\text{ V}$, $I_D = 17.5\text{ A}$	-	14	17	m Ω
		$V_{GS} = 4.5\text{ V}$, $I_D = 17.5\text{ A}$	-	16	20	

1. Specified by design, not tested in production.

Table 5. Dynamic

Symbol	Parameter	Test conditions	Min.	Typ.	Max.	Unit
C_{iss}	Input capacitance	$V_{DS} = 25\text{ V}$, $f = 1\text{ MHz}$, $V_{GS} = 0\text{ V}$	-	1700	-	pF
C_{oss}	Output capacitance		-	305	-	pF
C_{rss}	Reverse transfer capacitance		-	105	-	pF
Q_g	Total gate charge	$V_{DD} = 48\text{ V}$, $I_D = 55\text{ A}$, $V_{GS} = 0\text{ to }4.5\text{ V}$ (see the Figure 13. Test circuit for gate charge behavior)	-	25	33 ⁽¹⁾	nC
Q_{gs}	Gate-source charge		-	5	-	nC
Q_{gd}	Gate-drain charge		-	10	-	nC

1. Specified by design, not tested in production.

Table 6. Switching times

Symbol	Parameter	Test conditions	Min.	Typ.	Max.	Unit
$t_{d(on)}$	Turn-on delay time	$V_{DD} = 30\text{ V}$, $I_D = 27.5\text{ A}$, $R_G = 4.7\text{ }\Omega$, $V_{GS} = 4.5\text{ V}$	-	20	-	ns
t_r	Rise time		-	100	-	ns
$t_{d(off)}$	Turn-off delay time	(see the Figure 12. Test circuit for resistive load switching times and Figure 17. Switching time waveform)	-	40	-	ns
t_f	Fall time		-	20	-	ns

Table 7. Source-drain diode

Symbol	Parameter	Test conditions	Min.	Typ.	Max.	Unit
I_{SD}	Source-drain current		-	-	35	A
$I_{SDM}^{(1)}$	Source-drain current (pulsed)		-	-	140	A
$V_{SD}^{(2)}$	Forward on voltage	$I_{SD} = 35\text{ A}$, $V_{GS} = 0\text{ V}$	-	-	1.5	V
t_{rr}	Reverse recovery time	$I_{SD} = 35\text{ A}$, $di/dt = 100\text{ A}/\mu\text{s}$, $V_{DD} = 30\text{ V}$, $T_J = 150\text{ }^\circ\text{C}$ (see the Figure 14. Test circuit for inductive load switching and diode recovery times)	-	80	-	ns
Q_{rr}	Reverse recovery charge		-	200	-	nC
I_{RRM}	Reverse recovery current		-	5	-	A

1. Pulse width is limited by safe operating area.
2. Pulsed: pulse duration = 300 μs , duty cycle 1.5%.

2.1 Electrical characteristics (curves)

Figure 1. Safe operating area

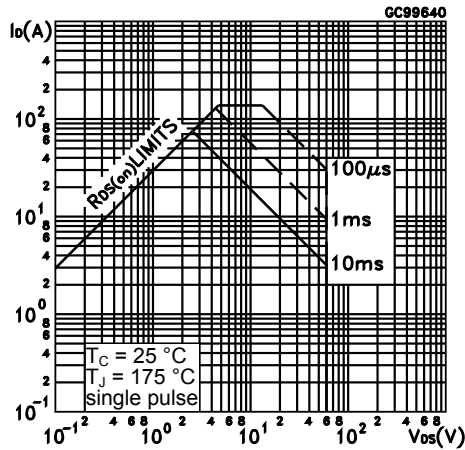


Figure 2. Normalized transient thermal impedance

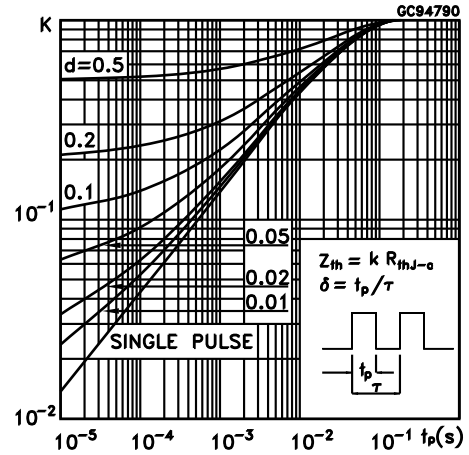


Figure 3. Typical output characteristics

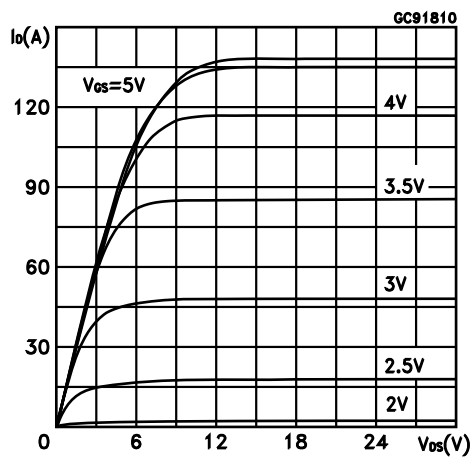


Figure 4. Typical transfer characteristics

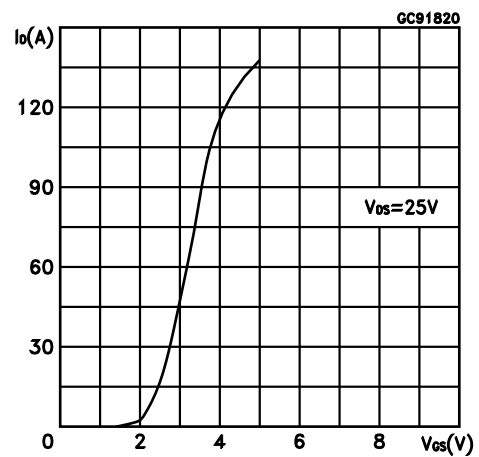


Figure 5. Typical gate charge characteristics

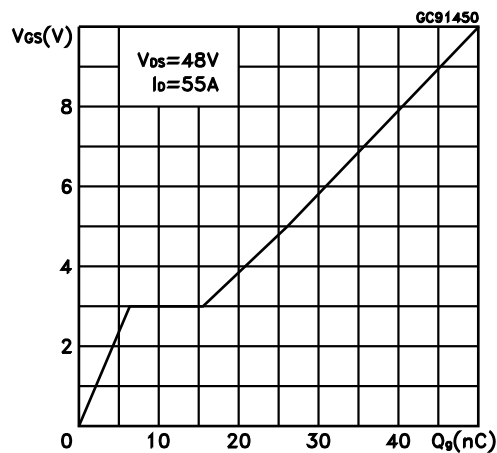


Figure 6. Typical capacitance characteristics

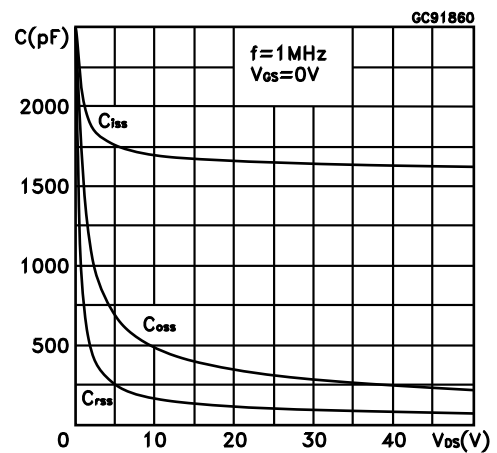


Figure 7. Normalized gate threshold vs temperature

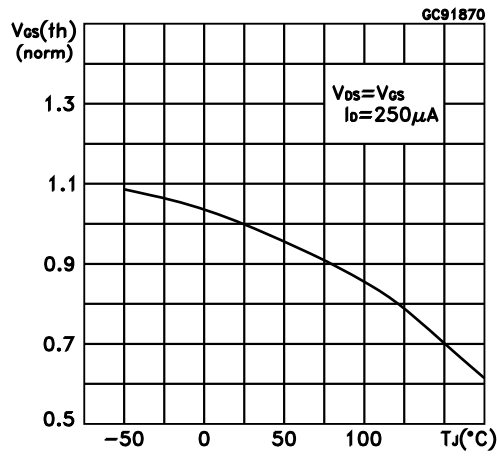


Figure 8. Normalized on-resistance vs temperature

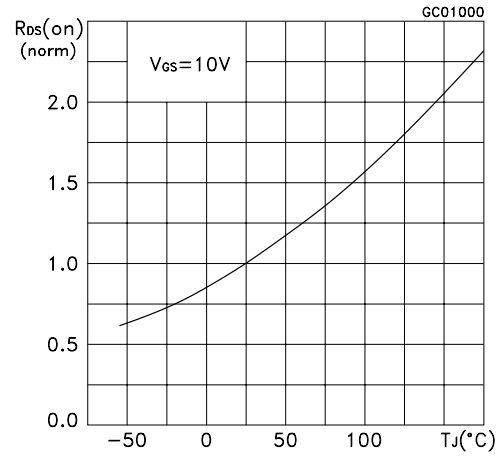


Figure 9. Typical drain-source on-resistance

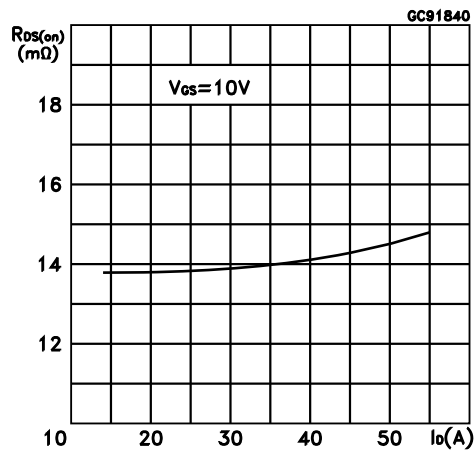


Figure 10. Normalized breakdown voltage vs temperature

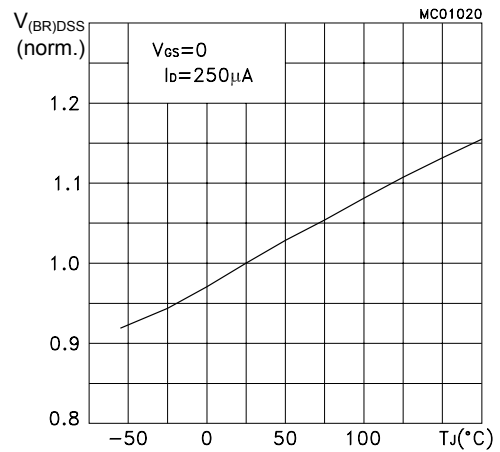
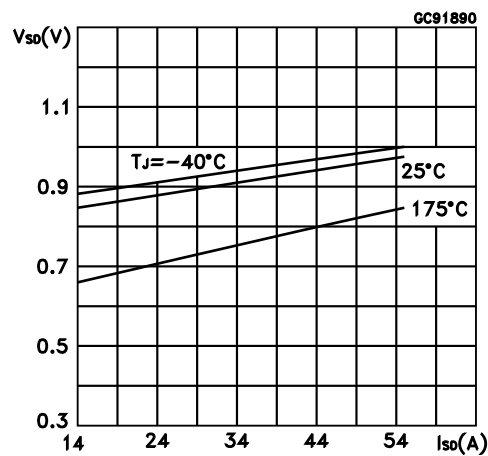
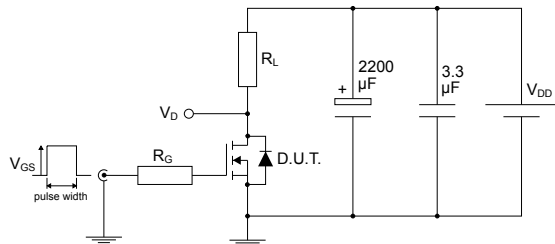


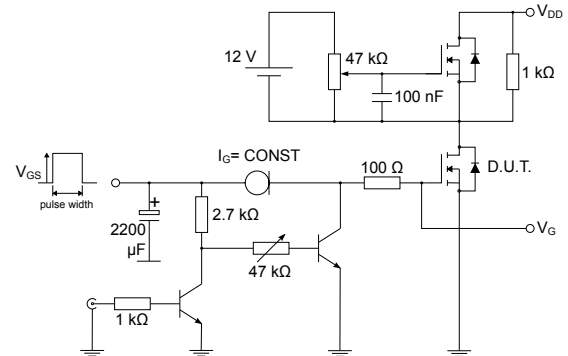
Figure 11. Typical reverse diode forward characteristics



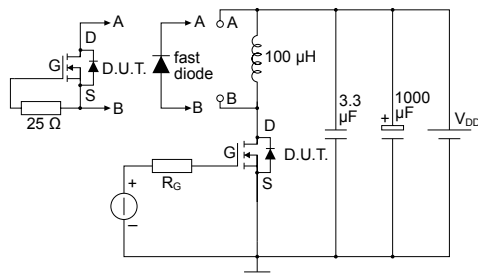
3 Test circuits

Figure 12. Test circuit for resistive load switching times


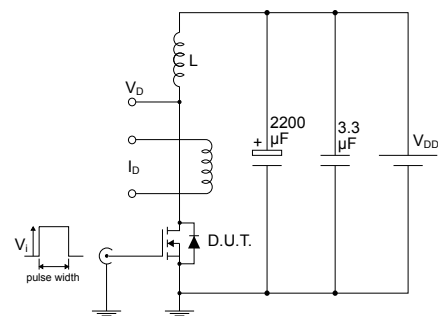
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Figure 13. Test circuit for gate charge behavior


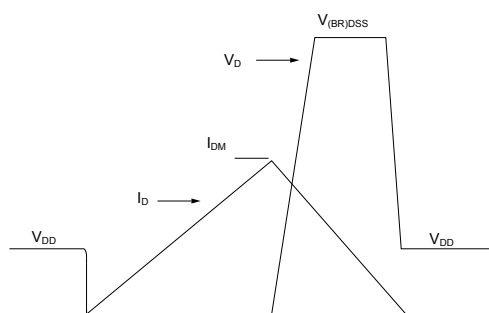
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Figure 14. Test circuit for inductive load switching and diode recovery times


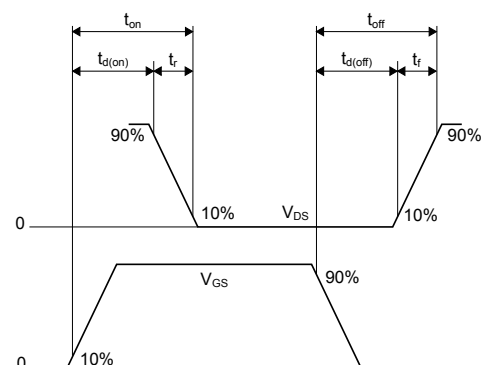
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Figure 15. Unclamped inductive load test circuit


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Figure 16. Unclamped inductive waveform


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Figure 17. Switching time waveform


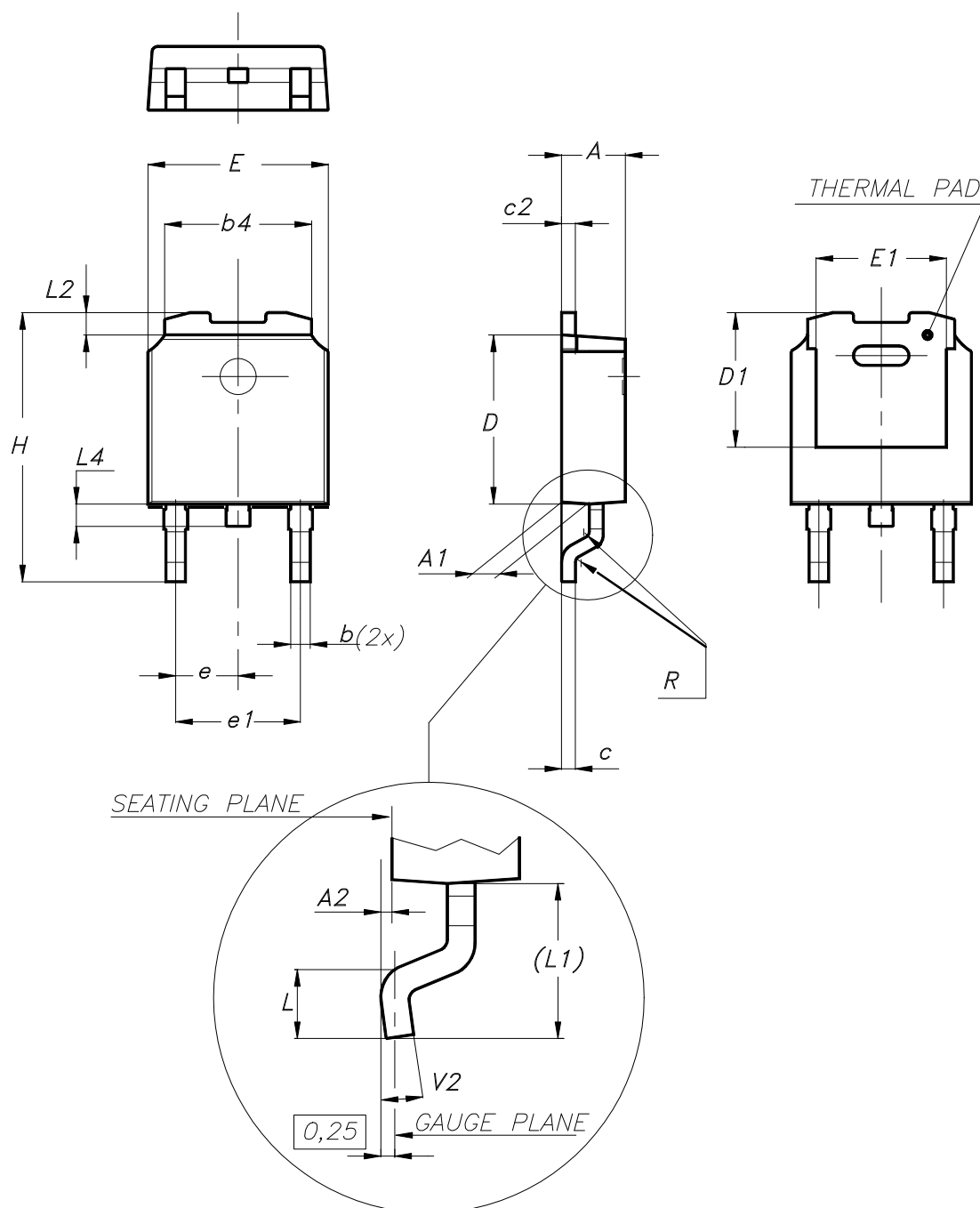
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4 Package information

To meet environmental requirements, ST offers these devices in different grades of **ECOPACK** packages, depending on their level of environmental compliance. ECOPACK specifications, grade definitions, and product status are available at: www.st.com. ECOPACK is an ST trademark.

4.1 DPAK (TO-252) package information

Figure 18. DPAK (TO-252) type A package outline

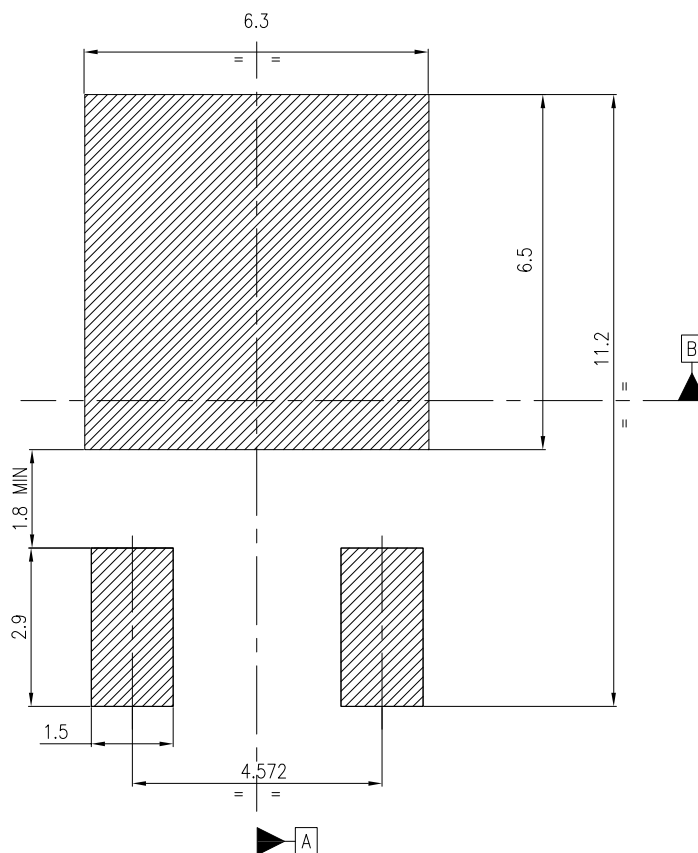


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Table 8. DPAK (TO-252) type A mechanical data

Dim.	mm		
	Min.	Typ.	Max.
A	2.20		2.40
A1	0.90		1.10
A2	0.03		0.23
b	0.64		0.90
b4	5.20		5.40
c	0.45		0.60
c2	0.48		0.60
D	6.00		6.20
D1	4.95	5.10	5.25
E	6.40		6.60
E1	4.60	4.70	4.80
e	2.159	2.286	2.413
e1	4.445	4.572	4.699
H	9.35		10.10
L	1.00		1.50
(L1)	2.60	2.80	3.00
L2	0.65	0.80	0.95
L4	0.60		1.00
R		0.20	
V2	0°		8°

Figure 19. DPAK (TO-252) recommended footprint (dimensions are in mm)



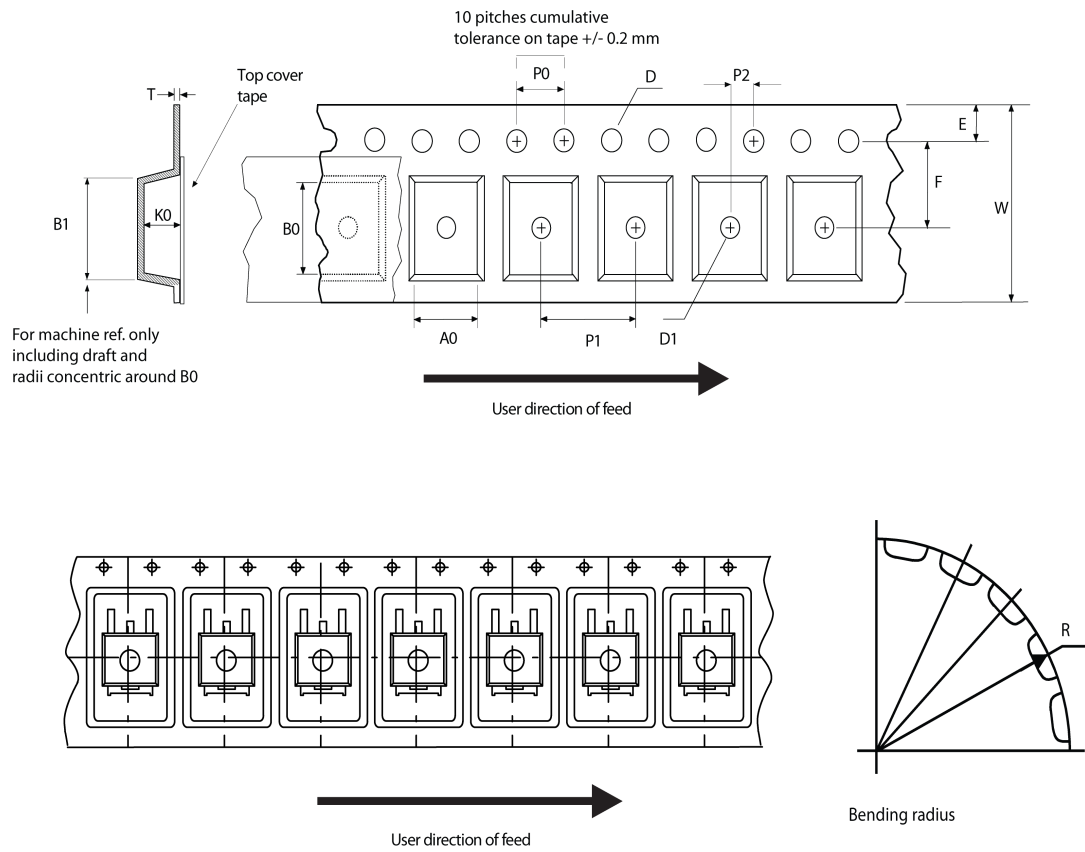
Notes:

- 1) This footprint is able to ensure insulation up to 630 Vrms (according to CEI IEC 664-1)
- 2) The device must be positioned within $\Phi 0.05$ A B

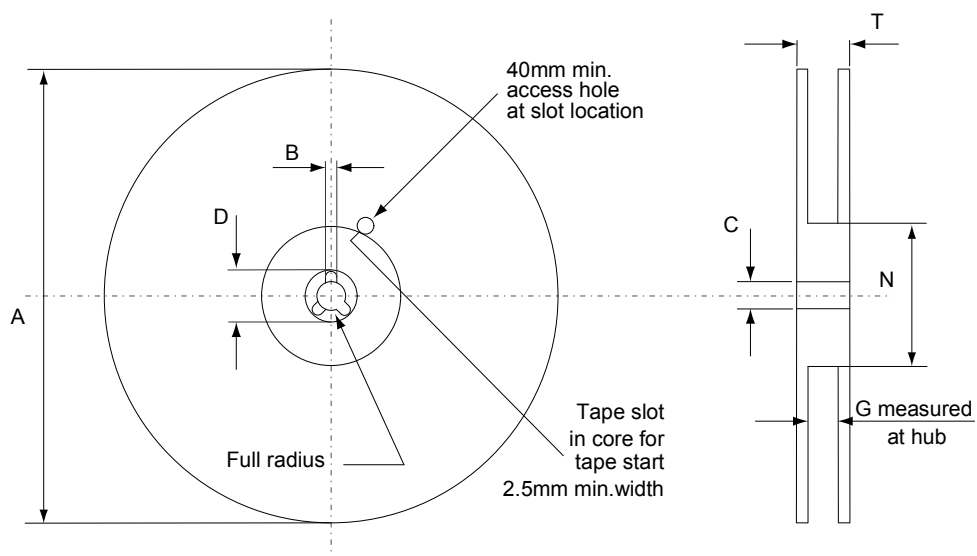
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4.2 DPAK packing information

Figure 20. DPAK tape outline



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Figure 21. DPAK reel outline


AM06038v1

Table 9. DPAK tape and reel mechanical data

Tape			Reel		
Dim.	mm		Dim.	mm	
	Min.	Max.		Min.	Max.
A0	6.8	7	A		330
B0	10.4	10.6	B	1.5	
B1		12.1	C	12.8	13.2
D	1.5	1.6	D	20.2	
D1	1.5		G	16.4	18.4
E	1.65	1.85	N	50	
F	7.4	7.6	T		22.4
K0	2.55	2.75			
P0	3.9	4.1	Base qty.		2500
P1	7.9	8.1	Bulk qty.		2500
P2	1.9	2.1			
R	40				
T	0.25	0.35			
W	15.7	16.3			

Revision history

Table 10. Document revision history

Date	Revision	Changes
21-Jun-2004	2	Preliminary version.
06-Jul-2006	3	New template, no content change.
20-Feb-2007	4	Typo mistake on page 1.
19-Apr-2012	5	Added new value in <i>Table 4: On/off states</i> ($V_{GS(th)}$ max).
03-Aug-2026	6	Updated Section 4: Package information . Minor text changes.

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